

Statement of Conformity

Reference No. : Conformity Report Reference : Issued Date : M00-CERT-CE-2203MAT104 22-03-MAT-104 Apr. 18, 2022

This statement of conformity is based on the <u>Electromagnetic</u> <u>Compatibility Directive of 2014/30/EU</u> and complied with the following EMC standards:

Emission:	Immunity:
EN 55032:2015	EN 55035:2017+A11:2020
EN 55032:2015+A11:2020	EN 61000-4-2:2009
CISPR32:2015	EN IEC 61000-4-3:2020
CISPR32:2015+A1:2019	EN 61000-4-4:2012
AS/NZS CISPR 32:2015, Class B	EN 61000-4-5:2014+A1:2017
EN 61000-3-2:2006 +A1:2009 +A2:2009	EN 61000-4-6:2014
EN 61000-3-3:2013	EN 61000-4-8:2010
	EN IEC 61000-4-11:2020

Company	:	Phihong Technology Co., Ltd.
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- Address : No. 568, Fuxing 3rd Rd., Guishan District, Taoyuan City, Taiwan.
- **Product Name :** SWITCHING POWER SUPPLY

Regulatory Model: PSAI05R-050QL6



~1~

Official stamp of the ETC

Paul Liao

(Signature)

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CONFORMANCE TEST REPORT FOR EN 55032 / EN 55035

Report No.: 22-03-MAT-104

According to:

■ Electromagnetic Compatibility Directive: 2014/30/EU

□ Low Voltage Directive: 2014/35/EU

□ Radio Equipment Directive: 2014/53/EU

□ Machinery Directives: 2006/42/EC

Applicant:	Phihong Technology Co., Ltd.					
Product:	SWITCHING POWER SUPPLY					
Model:	PSAI05R-05	0QL6				
Brand Name:	PHIHONG					
Date test item received:	2015/08/03	APPENDIX I:	2017/02/15	APPENDIX II: 2022/03/25		
Date test campaign completed:	2015/10/08	APPENDIX I:	2017/02/17	APPENDIX II: 2022/04/11		
Date of issue:	2015/10/12	APPENDIX I:	2017/02/20	APPENDIX II: >>>>/04/8		

The test result only corresponds to the tested sample. It is not permitted to copy this report, in part or in full, without the permission of the test laboratory. Total number of pages of APPENDIX II test report: 10 pages Total number of pages of ANNEX C test photos: 02 pages

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Laboratory Introduction: Taiwan Testing and Certification Center is recognized, filed and mutual recognition arrangement as following:

• ISO/IEC 17025 : TAF(0371), NVLAP(Lab code: 200133-0), CBTL(TÜV SÜD)

• Recognized : BSMI, NCC, FCC(TW1112), ISED(Industry Canada Site # 2949A-2)

S Filing : VCCI (C-13518, R-13177, G-10098, T-11682)

MRA : Australia, New Zealand, Singapore

ETC <u>TAIWAN TESTING AND CERTIFICATION CENTER</u> Report No.: 22-03-MAT-104

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Report Version History:

Report No.	Refer No.:	Date of issue	Difference
15-08-MAT-026	Initial	2015/10/12	
17-02-MAT-051	15-08-MAT-026	2017/02/20	 Adds EN 55032 standard for a new report. According to the added standards as above, only EMI will be influenced, it re-tests the test items.
22-03-MAT-104	17-02-MAT-051	2022/04/18	 Adds EN 55035 standard, updates standard from EN 55032:2015 to EN 55032:2015+A11:2020, from CISPR32:2015 to CISPR32:2015+A1:2019, from EN 61000-4-3:2006+A1:2008+A2:2010 to EN IEC 61000-4-3:2006+A1:2007+A2:2010 to IEC 61000-4-3:2020, from EN 61000-4-5:2006 to EN 61000-4-5:2014+A1:2017, from IEC 61000-4-5:2005 to IEC 61000-4-5:2014/AMD1:2017, from IEC 61000-4-6:2013 to IEC 61000-4-6:2013/AC: 2015, from EN 61000-4-11:2004 to EN IEC 61000-4-11:2020, from IEC 61000-4-11:2004 to IEC 61000-4-11:2020 to re-test. According to the updated standards as above and the differences of EN 55035 and 55024, some of the test items will be influenced, it re-tests RS, Surge and CS test items. As customer's request, it removes all of manufacturer's information, modified product name from SWITCHING ADAPTER to SWITCHING POWER SUPPLY, deletes EN 55022, EN 55024 standard and combines EN 55032 with EN 55035 standard for a one report.

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1 GENERAL INFORMATION

Applicant	[:] Phihong Technology Co., Ltd.			
Address	[:] No. 568, Fuxing 3rd Rd., Guishan District, Taoyuan City, Taiwan.			
EUT	SWITCHING POWER SUPPLY			
Brand Name	[:] PHIHONG			
Model No.	[:] PSAI05R-050QL6			
Test Standard	: Emissions EN 55032:2015 EN 55032:2015+A11:2020 CISPR32:2015 CISPR32:2015+A1:2019 AS/NZS CISPR 32:2015, Class B EN 61000-3-2:2006 +A1:2009 +A2:2009 IEC 61000-3-2:2005 +A1:2008 +A2:2009 EN 61000-3-3:2013 IEC 61000-3-3:2013	Immunity EN 55035:2017+A11:2020 EN 61000-4-2:2009 IEC 61000-4-2:2008 EN IEC 61000-4-3:2020 IEC 61000-4-3:2020 EN 61000-4-4:2012 IEC 61000-4-4:2012 EN 61000-4-5:2014+A1:2017 IEC 61000-4-5:2014/AMD1:2017 EN 61000-4-6:2014 IEC 61000-4-6:2013/AC: 2015 EN 61000-4-8:2010 IEC 61000-4-8:2009 EN IEC 61000-4-11:2020		

The testing described in this report has been carried out to the best of our knowledge and ability, and our responsibility is limited to the exercise of reasonable care. This testing is not intended to believe the sellers from their legal and/or contractual obligations. The compliance test is only certified for the test equipment and the results of the testing report relate only to the item tested. The compliance test of this report was conducted in accordance with the appropriate standards. When the EMC measurement uncertainty can meet the requirements of CISPR 16-4-2 standard, it is not included in the verification of test result. It's not intention to assure the quality and performance of the product. This report shall not be reproduced except in full, without the approval of ETC.

IEC 61000-4-11:2020

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2 GENERAL SPECIFICATION

2.1 Description of EUT:

The product is a SWITCHING POWER SUPPLY.

2.2 Related Information of EUT:

	Model: PSAI05R-050QL6		
Power Supply	: I/P: 100-240Vac, 50-60Hz, 0.3A		
	O/P: 5.0Vdc=1.0A, 5.0W MAX		
DC Power Line	: \blacksquare Nonshielded \square Shielded \square None,	length: <u>1.2</u>	m
LAN Cable(CAT-5e)	: \Box Nonshielded \Box Shielded \Box None,	length:	m

* For more detailed features, please refer to <u>User's Manual</u>.

2.3 Tested Peripheral:

The EUT connected with the following peripheral devices.

Following peripheral devices and interface cables were connected during the measurement: The Table of peripheral devices and interface cables

Product	Manufacturer Model No.		I/O Cable
Dummy Load			1.2m, Unshielded
Multimeter	KILTER	KILTER 370A	1.6m, Undetachable
	•		

2.4 Deviation Record:

(If any deviation from additions to or exclusions from test method must be stated)

<u>N/A</u>

2.5 Modification Record:

No modifications were required. (That is the EUT complied with the requirement as tested.)

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2.6 The Worst Mode for test:

2.6.1 Operating Conditions of the EUT.

Refer to EN55032 / CISPR 32:

The operational conditions of the EUT shall be determined by the manufacturer according to the typical use of the EUT with respect to the expected highest level of emission. The determined operational mode and the rationale for the conditions shall be stated in the test report.

The EUT shall be operated within the rated (normal) operating voltage range and typical load conditions (mechanical and electrical) for which it is designed. Actual loads should be used whenever possible. If a simulator is used ,it shall represent the actual load with respect to its radio frequency and functional characteristics.

The test programmers or other means of exercising the equipment should ensure that various parts of a system exercised in a manner that permits detection of all system disturbances. For example, in a computer system, tape and disk drivers should be put through a mechanical read-write-erase sequence; and various portions of memories should be addressed. Any mechanical activities should be performed.

Refer to AS/NZS CISPR 32:

The operational conditions of the EUT shall be determined by the manufacturer according to the typical use of the EUT with respect to the expected highest level of emission. The determined operational mode and the rationale for the conditions shall be stated in the test report.

The EUT shall be operated within the rated (normal) operating voltage range and typical load conditions (mechanical and electrical) for which it is designed. Actual loads should be used whenever possible. If a simulator is used, it shall represent the actual load with respect to its radio frequency and functional characteristics.

The test programmes or other means of exercising the equipment should ensure that various parts of a system exercised in a manner that permits detection of all system disturbances. For example, in a computer system, tape and disk drivers should be put through a mechanical read-write-erase sequence; and various portions of memories should be addressed. Any mechanical activities should be performed and visual display units should be operated as in Annex B.

Refer to EN55035:

The test shall be made exercising all primary functions in the most representative mode consistent with typical applications. The test sample shall be configured in a manner consistent with typical installation practice. If the equipment is part of a system or can be connected to auxiliary equipment, then the equipment shall be test while connected to the minimum representative configuration of auxiliary equipment necessary to exercise the ports in a similar manner to that described in CISPR22.

The configuration and mode of operating during the tests shall be precisely noted in the test report. It is not always possible to test every function of the apparatus; in such cases , the most critical mode of operation shall be selected.

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2.6.2 Testing Setup Block Diagram



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3 SUMMARY OF TEST RESULTS

3.1 Emissions:

3.1.1 Conducted Emissions

-PASS

QP EMI value to the limit:

-10.81 dB at 2.6620 MHz

3.1.2 Radiated Emissions

-PASS

QP EMI value to the limit:

-4.57 dB at 61.1022 MHz

3.1.3 Harmonics Current Emissions

-Pass

The harmonics current values were under the limits of the class A equipment of the EN 61000-3-2.

3.1.4 Voltage Fluctuations and Flicker

-Pass

The voltage fluctuations and flicker values were under the limits of the EN 61000-3-3 requirements.

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3.2 Immunity:

3.2.1 Immunity Criteria:

The results of all of the immunity tests performed on the EUT were evaluated according to the following criteria, and according to the manufacturer's specifications for the EUT:

- **Performance criterion A:** The EUT continued to operate as intended. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended.
- **Performance criterion B:** The EUT continued to operate as intended after the test. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended. During the test, degradation of performance was however allowed. No change of actual operating state or stored data was allowed.
- **Performance criterion C:** Temporary loss of function was allowed, provided the function was self recoverable or could be restored by the operation of the controls.

3.2.2 Electrostatic Discharge Immunity:

- - No Degradation of Function
- □ Distortion of Function
- \Box Error of Function

3.2.3 RF Radiated Fields Immunity:

- - No Degradation of Function
- □ Distortion of Function
- □ Error of Function

Requirement: Criterion B (or better) - Satisfies Criterion A

- Satisfies Criterion B
- Satisfies Criterion B
- Satisfies Criterion C

Requirement: Criterion A

- Satisfies Criterion A
- Satisfies Criterion B
- Satisfies Criterion C

3.2.4 EFT/Burst Immunity:

- - No Degradation of Function
- □ Distortion of Function
- \Box Error of Function

Requirement: Criterion B (or better)

- Satisfies Criterion A
- Satisfies Criterion B
- Satisfies Criterion C

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3.2.5 Surge Immunity:

- - No Degradation of Function
- □ Distortion of Function
- \Box Error of Function

3.2.6 RF Common Mode Immunity:

- No Degradation of Function
- □ Distortion of Function
- \Box Error of Function

Requirement: Criterion B (or better)

- Satisfies Criterion A
- Satisfies Criterion B
- Satisfies Criterion C

Requirement: Criterion A

- Satisfies Criterion A
- Satisfies Criterion B
- Satisfies Criterion C

3.2.7 Power Frequency Magnetic Field Immunity:

- No Degradation of Function
- □ Distortion of Function
- \Box Error of Function

Requirement: Criterion A

- Satisfies Criterion B

3.2.8 Voltage Interruptions and Voltage Dips Immunity:

Requirement: Criterion C (or better)

- Satisfies Criterion A
 - Satisfies Criterion B
 - Satisfies Criterion C
- – No Degradation of Function
- – Distortion of Function
- \Box Error of Function

- - Satisfies Criterion A

 - Satisfies Criterion C

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3.3 Summary of test Results and Applied Level:

Manufacturer level requirements: (Custom's Specification)

since and the second se	Summary of test Results and Applied Level					
~	Emission	<u></u>				
Test Standard	Test Item	Test Result	Applied Level and M.U.			
EN 55022: 2010 + AC:2011 / CISPR 22:2008 / AS/NZS CISPR 22:2009 + A1:2010,Class B	Radiated Emission	PASS	ClassB @30MHz~1GHz, U=±4.74dB @1GHz~6GHz, U=±4.96dB			
EN 55022: 2010 + AC:2011 / CISPR 22:2008 / AS/NZS CISPR 22:2009 + A1:2010,Class B	Conducted Emission	PASS	Class B @AC Port: 0.15MHz~30MHz, U=±2.92dB @ISN: 0.15MHz~30MHz, U=±3.00dB			
EN 61000-3-2:2006 +A1:2009 +A2:2009 / IEC 61000-3-2:2005 +A1:2008 +A2:2009, Class A	Harmonic Current Emission	PASS	Class A @MU, U=±1.283%			
EN 61000-3-3:2013 / IEC 61000-3-3:2013	Voltage Fluctuation and Flicker Test	PASS	All parameter @MU, U=±1.283%			
	Immunity [EN 55024:	2010]				
EN 61000-4-2:2009 / IEC 61000-4-2:2008	Electrostatic Discharge Test (ESD)	PASS	 @Contact Discharge up to <u>±4KV</u> @Air Discharge up to <u>±8KV</u> @measurement uncertainty U=±56V 			
EN 61000-4-3:2006+A1:2008+A2:2010 / IEC 61000-4-3:2006+A1:2007+A2:2010	Radiated , RF Immunity (RS)	PASS	 @Frequency: <u>80MHz-1000MHz</u> @3V/m (Unmodulated), 1KHz Amplitude Modulated with modulation depth 80% @measurement uncertainty U=±1.37 			
EN 61000-4-4:2012 / IEC 61000-4-4:2012	Electrical Fast Transient/burst Test (EFT)	PASS	@Power port : <u>±1KV</u> @measurement uncertainty U=±2.95V			
EN 61000-4-5:2006 / IEC 61000-4-5:2005	Surge Immunity	PASS	@Power port : <u>±0.5KV, ±1KV</u> @measurement uncertainty U=±3.55V			
EN 61000-4-6:2014 / IEC 61000-4-6:2013	Conducted , RF Immunity (CS)	PASS	 @Frequency: <u>0.15MHz-80MHz</u> @3V/m (Unmodulated), 1KHz Amplitude Modulated with modulation depth 80% @measurement uncertainty U=±2.3 			
EN 61000-4-8:2010 / IEC 61000-4-8:2009	Power Frequency Magnetic Field (MS)	PASS	1A/m , 50Hz			
EN 61000-4-11:2004 / IEC 61000-4-11:2004	Voltage dips,short interruptions and voltage variations on power supply input lines	PASS	>95% Voltage variation , 5s >95% Voltage DIP , 10ms 30% Voltage DIP , 500ms @measurement uncertainty U=±3.55			

Note : Measurement uncertainty $U=\pm X$. Means the expanded measure uncertainty $U=\pm X$, the coverage factor k=2, approximately a 95% level of confidence.

4 TEST DATA & RELATED INFORMATIONS

4.1 Emissions:

4.1.1 Conducted Emissions Test:

4.1.1.1 Conducted Emissions Test Data:

A. Operating Conditions of the EUT: Full Load

 Test Date:
 Oct. 05, 2015
 Temperature:
 23 °C

Humidity: <u>59 %</u>

(Phase:L) 80.0 dBuV



No.	Frequency	Reading	Detector	Corrected	Result	Limit	Margin
	(MHz)	(dBuV)		dB	(dBuV)	(dBuV)	(dB)
1	0.1940	36.54	QP	9.65	46.19	63.86	-17.67
2	0.3700	32.72	QP	9.66	42.38	58.50	-16.12
3	1.5020	32.15	QP	9.69	41.84	56.00	-14.16
4	2.6780	34.68	QP	9.72	44.40	56.00	-11.60
5	4.3660	32.04	QP	9.74	41.78	56.00	-14.22
6	9.0460	34 80	OP	9.81	44.61	60.00	-15.39

Notes: 1) Place of measurement: EMC LAB. of the ETC (2F)

- 2) The EUT was placed 0.8m above reference ground plane.
- 3) Example calculation : result for 0.1940 MHz: $36.54+9.65 = 46.19 \text{ dB}\mu\text{V}$
- 4) ① If the data table appeared symbol of "***" means the value was too low to be measured.
 ② If the data table appeared symbol of "----" means the Q.P. value is under the limit for

② If the data table appeared symbol of "----" means the Q.P. value is under the limit for AVG. so, the AVG. value doesn't need to be measured.

- ③ If the data table appeared symbol of "#" means the noise was low, so record the peak value.
- 5) The expanded measure uncertainty, mean the coverage factor k=2, approximately a 95% level of confidence.

±2.92dB. (0.15MHz~30MHz)

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No.	Frequency	Reading	Detector	Corrected	Result	Limit	Margin
	(MHz)	(dBuV)		dB	(dBuV)	(dBuV)	(dB)
1	0.4980	33.27	QP	9.64	42.91	56.03	-13.12
2	1.4900	32.90	QP	9.67	42.57	56.00	-13.43
3	1.9340	34.62	QP	9.69	44.31	56.00	-11.69
4	2.6620	35.49	QP	9.70	45.19	56.00	-10.81
5	4.1660	34.15	QP	9.72	43.87	56.00	-12.13
6	8.6740	37.25	QP	9.81	47.06	60.00	-12.94

Notes: 1) Place of measurement: EMC LAB. of the ETC (2F)

2) The EUT was placed 0.8m above reference ground plane.

- 3) Example calculation : result for 0.4980 MHz: $33.27+9.64 = 42.91 \text{ dB}\mu\text{V}$
- 4) ① If the data table appeared symbol of "***" means the value was too low to be measured.

⁽²⁾ If the data table appeared symbol of "----" means the Q.P. value is under the limit for AVG. so, the AVG value doesn't need to be measured.

Av 0. so, the Av 0. value doesn't need to be measured.

③ If the data table appeared symbol of "#" means the noise was low, so record the peak value.

5) The expanded measure uncertainty, mean the coverage factor k=2, approximately a 95% level of confidence.

±2.92dB. (0.15MHz~30MHz)

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No.	Frequency	Reading	Detector	Corrected	Result	Limit	Margin
	(MHz)	(dBuV/m)		dB/m	(dBuV/m)	(dBuV/m)	(dB)
1	31.5545	39.79	QP	-17.52	22.27	30.00	-7.73
2	67.3077	42.72	QP	-17.70	25.02	30.00	-4.98
3	78.1891	40.98	QP	-18.97	22.01	30.00	-7.99
4	155.9135	30.11	QP	-6.06	24.05	30.00	-5.95
5	174.5673	29.96	QP	-8.77	21.19	30.00	-8.81
6	247.6282	30.48	QP	-12.84	17.64	37.00	-19.36

Notes: 1) Place of Measurement: Measuring site of the ETC (1F)

- 2) Measurement Distance: <u>10 m</u>
- 3) Height of table on which the EUT was placed: 0.8 m
- 4) Height of Receiving Antenna: <u>1 4 m</u>
- 6) ① If the data table appeared symbol of "***" means the value was too low to be measured.
 ② If the data table appeared symbol of "#" means the noise was low, so record the peak value.
- 7) The expanded measure uncertainty, mean the coverage factor k=2, approximately a 95% level of confidence.
 - $+ 4.94 dB / 4.94 dB (30 MHz) \leq f \leq 300 MHz$
 - + 4.94dB / 4.94dB (300MHz $\leq f \leq 1$ GHz)
 - + 5.1dB / 5.1dB (1GHz $\leq f \leq 6$ GHz)
 - + 4.58dB / 4.58dB (6GHz $\leq f \leq$ 18GHz)

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No.	Frequency	Reading	Detector	Corrected	Result	Limit	Margin
	(MHz)	(dBuV/m)		dB/m	(dBuV/m)	(dBuV/m)	(dB)
1	53.3267	41.56	QP	-16.40	25.16	30.00	-4.84
2	61.1022	41.62	QP	-16.19	25.43	30.00	-4.57
3	105.8116	34.06	QP	-15.78	18.28	30.00	-11.72
4	127.1944	34.44	QP	-11.48	22.96	30.00	-7.04
5	154.4088	29.96	QP	-5.66	24.30	30.00	-5.70
6	243.8277	32.71	QP	-13.55	19.16	37.00	-17.84

- Notes: 1) Place of Measurement: Measuring site of the ETC (1F)
 - 2) Measurement Distance: 10 m
 - 3) Height of table on which the EUT was placed: 0.8 m
 - 4) Height of Receiving Antenna: <u>1 4 m</u>
 - 5) Example Calculation : result for 53.3267 MHz: $41.56 + (-16.40) = \frac{25.16 \text{ dB}\mu\text{V/m}}{1000 \text{ dB}\mu\text{V/m}}$
 - 6) ① If the data table appeared symbol of "***" means the value was too low to be measured.
 ② If the data table appeared symbol of "#" means the noise was low, so record the peak value.
 - 7) The expanded measure uncertainty, mean the coverage factor k=2, approximately a 95% level of confidence.
 - + 4.98dB / 4.98dB (30MHz $\leq f \leq$ 300MHz)
 - + 4.98dB / 4.98dB (300MHz $\leq f \leq 1$ GHz)
 - + 5.18dB / 5.18dB (1GHz $\leq f \leq$ 6GHz)
 - + 4.9dB / 4.9dB (6GHz $\leq f \leq$ 18GHz)

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4.1.3 Harmonics Current Emissions Test:

4.1.3.1 Harmonics Current Emissions Test Data:

A. Operating Conditions of the EUT: Full Load

Test Date: Oct. 05, 2015

Test Specification	IEC 61000-3-2:2005 +A1:2008 +A2:2009	
Climatic Condition	Ambient Temperature: <u>23°</u> C	Relative Humidity: <u>51 %</u> RH
Power Supply System	AC Power: <u>230</u> Vac <u>50</u> Hz	

Test data see the next page.

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Report title:	
Company Name:	
Date of test:	15:35 5.Oct 2015
Measurement file name:	Harmonics_3_2_Ed3.rsd
Tester:	
Standard used:	EN/IEC 61000-3-2 Ed.3 Long cyclic
	Equipment class A <= 150% of the limit (Limit factor: 1.00)
Observation time:	180s
Windows width:	10 periods - (EN/IEC 61000-4-7 Edition 2002 + A1:2008)
Customer:	
E. U. T.:	Switching Power Supply (PSAIO5R-050QL6)
Temperature :	
Humidity :	

Test Result	
E. U. T.:	PASS
Power Source:	PASS

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E. U. T. Result

Check harmonics 2..40 [exception odd 21..39]:

Harmonic(s)) > 150%:	
	Order (n):	None
Harmonic(s)) with average >	100%:
	Order (n):	None

Check odd harmonics 21..39:

All Partial Odd Harmonics below partial limits.				
Harmonic(s) > 150%:				
	Order (n):	None		
Harmonic(s) with average > 150%:				
	Order (n):	None		

Power Source Result

First dataset out of limit:					
DS (time):	None				
Harmonic(s) out of limit:	Harmonic(s) out of limit:				
Order (n):	None				

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Average harmonic current results						
Hn	Ieff [A]	% of Limit	Limit [A]	Result		
1	28.153E-3					
2	1.243E-3			PASS		
3	25.541E-3	1.110	2.30	PASS		
4	1.333E-3			PASS		
5	23.663E-3	2.076	1.14	PASS		
6	1.141E-3			PASS		
7	21.373E-3	2.776	770.00E-3	PASS		
8	933.519E-6			PASS		
9	18.591E-3	4.648	400.00E-3	PASS		
10	885.563E-6			PASS		
11	15.582E-3	4.722	330.00E-3	PASS		
12	870.195E-6			PASS		
13	12.430E-3	5.919	210.00E-3	PASS		
14	1.044E-3			PASS		
15	9.508E-3	6.338	150.00E-3	PASS		
16	915.070E-6			PASS		
17	7.098E-3	5.363	132.35E-3	PASS		
18	1.306E-3			PASS		
19	5.335E-3	4.505	118.42E-3	PASS		
20	883.021E-6			PASS		
21	4.423E-3			PASS		
22	879.094E-6			PASS		
23	4.162E-3			PASS		
24	866.974E-6			PASS		
25	4.115E-3			PASS		
26	849.693E-6			PASS		
27	3.954E-3			PASS		
28	995.798E-6			PASS		
29	3.622E-3			PASS		
30	826.698E-6			PASS		
31	3.131E-3			PASS		
32	969.885E-6			PASS		
33	2.642E-3			PASS		
34	835.042E-6			PASS		
35	2.164E-3			PASS		
36	831.112E-6			PASS		
37	1.910E-3			PASS		
38	836.413E-6			PASS		
39	1.739E-3			PASS		
40	840.161E-6			PASS		

Harmonic currents less than 0.6% of the input current measured under the test conditions, or less than 5 mA, whichever is greater, are disregarded.

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Maximum harmonic current results						
Hn	Ieff [A]	% of Limit	Limit [A]	Result		
1	28.951E-3					
2	1.493E-3			PASS		
3	26.150E-3	0.758	3.45	PASS		
4	1.524E-3			PASS		
5	24.204E-3	1.415	1.71	PASS		
6	1.418E-3			PASS		
7	21.781E-3	1.886	1.15	PASS		
8	1.058E-3			PASS		
9	18.925E-3	3.154	600.00E-3	PASS		
10	981.455E-6			PASS		
11	15.943E-3	3.221	495.00E-3	PASS		
12	981.013E-6			PASS		
13	12.661E-3	4.019	315.00E-3	PASS		
14	1.221E-3			PASS		
15	9.726E-3	4.322	225.00E-3	PASS		
16	1.165E-3			PASS		
17	7.275E-3	3.665	198.52E-3	PASS		
18	1.482E-3			PASS		
19	5.561E-3	3.131	177.63E-3	PASS		
20	1.021E-3			PASS		
21	4.677E-3			PASS		
22	985.655E-6			PASS		
23	4.845E-3			PASS		
24	984.512E-6			PASS		
25	4.393E-3			PASS		
26	970.415E-6			PASS		
27	4.179E-3			PASS		
28	1.153E-3			PASS		
29	3.801E-3			PASS		
30	929.380E-6			PASS		
31	3.287E-3			PASS		
32	1.103E-3			PASS		
33	2.852E-3			PASS		
34	947.595E-6			PASS		
35	2.351E-3			PASS		
36	931.953E-6			PASS		
37	2.058E-3			PASS		
38	990.702E-6			PASS		
39	1.863E-3			PASS		
40	957.472E-6			PASS		

Harmonic currents less than 0.6% of the input current measured under the test conditions, or less than 5 mA, whichever is greater, are disregarded.

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Maximum harmonic voltage results						
Hn	Ueff [V]	Ueff [%]	Limit [%]	Result		
1	231.68	100.731				
2	108.31E-3	0.047	0.2	PASS		
3	61.13E-3	0.027	0.9	PASS		
4	35.98E-3	0.016	0.2	PASS		
5	37.89E-3	0.016	0.4	PASS		
6	32.12E-3	0.014	0.2	PASS		
7	67.89E-3	0.030	0.3	PASS		
8	28.47E-3	0.012	0.2	PASS		
9	81.37E-3	0.035	0.2	PASS		
10	8.76E-3	0.004	0.2	PASS		
11	54.77E-3	0.024	0.1	PASS		
12	7.34E-3	0.003	0.1	PASS		
13	43.00E-3	0.019	0.1	PASS		
14	29.01E-3	0.013	0.1	PASS		
15	63.59E-3	0.028	0.1	PASS		
16	24.90E-3	0.011	0.1	PASS		
17	13.96E-3	0.006	0.1	PASS		
18	19.20E-3	0.008	0.1	PASS		
19	53.30E-3	0.023	0.1	PASS		
20	23.19E-3	0.010	0.1	PASS		
21	65.29E-3	0.028	0.1	PASS		
22	15.62E-3	0.007	0.1	PASS		
23	31.47E-3	0.014	0.1	PASS		
24	9.30E-3	0.004	0.1	PASS		
25	30.90E-3	0.013	0.1	PASS		
26	14.04E-3	0.006	0.1	PASS		
27	49.90E-3	0.022	0.1	PASS		
28	15.21E-3	0.007	0.1	PASS		
29	43.65E-3	0.019	0.1	PASS		
30	15.11E-3	0.007	0.1	PASS		
31	22.84E-3	0.010	0.1	PASS		
32	13.36E-3	0.006	0.1	PASS		
33	41.45E-3	0.018	0.1	PASS		
34	19.54E-3	0.008	0.1	PASS		
35	36.20E-3	0.016	0.1	PASS		
36	8.42E-3	0.004	0.1	PASS		
37	28.17E-3	0.012	0.1	PASS		
38	14.46E-3	0.006	0.1	PASS		
39	34.17E-3	0.015	0.1	PASS		
40	16.59E-3	0.007	0.1	PASS		

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4.1.4 Voltage Fluctuations and Flicker Test:

4.1.4.1 Voltage Fluctuations and Flicker Test Data:

A. Operating Conditions of the EUT: Full Load

Test Date: Oct. 05, 2015

Test Specification	EC 61000-3-3 :2013					
Climatic Condition	Ambient Temperature: <u>23°</u> C	Relative Humidity: <u>60 %</u> RH				
Power Supply System	AC Power: <u>230</u> Vac <u>50</u> Hz					

Test data see the next page.

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Test Report

Report title:	
Company Name:	
Date of test:	15:50 5.Oct 2015
Tester:	
Standard used:	EN/IEC 61000-3-3 Ed.3 Flicker
Short time (Pst):	10 min
Observation time:	10 min (1 Flicker measurement)
Flickermeter:	230V / 50Hz according IEC 61000-4-15 Ed.2
Flicker Impedance:	Zref (IEC 60725)
Customer:	
E. U. T.:	
Temperature :	
Humidity :	

Test Result

PASS

Maximum Flicker results

	EUT values	Limit	Result
Pst	0.028	1.00	PASS
Plt	0.028	0.65	PASS
dc [%]	0.000	3.30	PASS
dmax [%]	0.051	7.00	PASS
dt [s]	0.000	0.50	PASS

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4.2 Immunity:

4.2.1 Electrostatic Discharge Immunity Test: 4.2.1.1 Electrostatic Discharge Immunity Test Data:

A. Operating Conditions of the EUT: Full Load

Project number	PSAI05R-05	0QL6	Test Dated	2015/10/8			
Test Specification	IEC 61000-4	2:2008					
Test Equipmer	nt	Calibration Date	Recommended Recal. Date				
Electrostatic Discharge EMTEST/ Noise	Jul. 04, 2015	Jul. 03, 2016					
Climatic Condition		Ambient Temperature : $20 \degree$ C Relative Humidity : 38% RH Atmospheric Pressure: 997 mbar					
Test Set-up	■ Table-top I	Equipment	nent				
Power Supply System	■ AC Power:	230 Vac <u>50</u> Hz DC Pov	wer: <u>V</u> dc				
Energy-Storage Capacito	Energy-Storage Capacitor : <u>150</u> pF Discharge Resistor : <u>330</u> Ω						
Operating Conditions of The Device Full Load							

Test Points	st Points Contact Discharge (kv) : Criterion			Air Discharge (kv) : Criterion					xv) : Cr	Test times and voltage at each condition							
1.EUT-VCP	$\frac{2}{\underline{A}}$:		4 <u>A</u>	:	6	:	8:	:	2	:	4	:	8:	12 :	15:	■25neg	■25pos
2.EUT-HCP	2 : <u>A</u>		4 A	:	6	:	8:	:	2	:	4	:	8:	12 :	15:	■25neg	■25pos
3.1~6	2 :	1	4	:	6	:	8:	:	2	:	4 <u>A</u>	:	8: <u>A</u>	12 :	15:	∎10neg	■10pos

*The test point of esd . Blue color mean test point apply air discharge , red color mean test point apply contact discharge.

Result:	■ Complied		
Criterion Required:	<u>B</u>	Criterion Met:	A

Note:"A" means the EUT normal performance within limits specified by manufacturer, requestor or purcher.

"B" means the EUT temporary loss of function or degradation of performance which ceases after the disturbance ceases, and from which the equipment under test recovers its normal performance, without operator intervention.



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4.2.1.2 Electrostatic Discharge Immunity Test Block Diagram



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4.2.2 Radio Frequency Electromagnetic Field Test: 4.2.2.1 Radio Frequency Electromagnetic Field Test Data:

A. Operation	ng Conditions of the EUT: <u>Full Load</u>				
Test Date	Oct. 07, 2015				
Test Specification	EC 61000-4-3:2006+A1:2007+A2:2010				
Model Number		Series :			
Power Supply Model Num.	PSAI05R-050QL6	Manufacturer :			
Climatic Condition	Ambient Temperature:27°CRAtmospheric Pressure:996 mbar	elative Humidity: <u>45 %</u> RH			
Test Mode	Full Load				
Power Supply System	AC Power: <u>230</u> Vac <u>50</u> Hz				
Test Set-up	Table-top Equipment				

Frequency Range : <u>80</u> MHz ~ <u>100</u>	00 MHz Field St	trength : <u>3</u> V/m	Modulation	(AM 1kHz 80%)
Sweep Rate $\therefore \le 1.5 \times 10^{-3}$ decades/s	Step Size $\therefore \le 1 \%$	6 of preceding frequenc	zy value	Dwell Time $: 5 \text{ s}$
Frequency Range (MHz)	Polarization of Antenna	EUT Position (Angle)	Test Result	Comments
<u>80</u> MHz ~ <u>1000</u> MHz	Vertical	0	А	
<u>80</u> MHz ~ <u>1000</u> MHz	Vertical	90	А	
<u>80</u> MHz ~ <u>1000</u> MHz	Vertical	180	А	
<u>80</u> MHz ~ <u>1000</u> MHz	Vertical	270	А	
<u>80</u> MHz ~ <u>1000</u> MHz	Horizontal	0	А	
<u>80</u> MHz ~ <u>1000</u> MHz	Horizontal	90	А	
<u>80</u> MHz ~ <u>1000</u> MHz	Horizontal	180	A	
<u>80</u> MHz ~ <u>1000</u> MHz	Horizontal	270	А	

Result:	■ Complied	□ Does not comply				
Criterion Required:	А	Criterion Met:	А	PASS		
		1 3 1 1 1 0 0	1 6.6			

(1)Note: " A "means the EUT continued to operate as intended. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended.

(2)Note: "B "means the EUT continued to operate as intended after the test. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended. During the test, degradation of performance was however allowed. No change of actual operating state or stored data was allowed.

(3)Note: "C "means the EUT temporary loss of function was allowed, provided the function was self recoverable or could be restored by the operation of the controls.

(4)Additional Information :

The frequency range is scaned as specified. However, when specified in Annex A, an additional comprehensive functional test shall carried out at a limited number of frequencies. And additional frequencies tested for Korean KN24. The selected frequencies are : 80, 120, 145, 160, 230, 375, 434, 435, 460, 600, 814, 835, 863, and $900MHz(\pm1\%)$.

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4.2.2.2 RF Radiated Fields Immunity Test Block Diagram

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4.2.3 Fast Transients Common Mode Test: 4.2.3.1 Fast Transients Common Mode Test Data: A.Operating Conditions of the EUT: <u>Full Load</u>

A. Test Port : Main Power

	V -			
Test Date	Oct. 08 , 2015			
Test Specification	EC 61000-4-4:2012			
Model Number		Series : N\A		
Power Supply Model Num.	PSAI05R-050QL6	Manufacturer : N\A		
Climatic Condition	Ambient Temperature: <u>27</u> C Re	elative Humidity: <u>45 %</u> RH		
	Atmospheric Pressure: <u>996</u> mbar			
Test Mode	Full Load			
Power Supply System	AC Power: <u>230</u> Vac <u>50</u> Hz			
Test Set-up	Table-top Equipment			

Pulse: 5 Burst: 15	/50ns Repe 5ms /300ms	etition Rate: <u>2.5kHz</u> ab <u>5kHz</u> bel	ove 2.0kV low and equal 2.0kV	Test time: <u>1</u> min/each condition		
Applied Voltage	Test Line	Severity Level	Test Duration (min)	Test Result	Comments	
	L	2	1	А		
±1KV	Ν	2	1	А		
	L+N	2	1	А		

Result:	■ Complied	Does not comply			
Criterion Required:	1KV	В	Criterion Met:	А	PASS

(1)Note: " A "means the EUT continued to operate as intended. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended.

(2)Note: "B "means the EUT continued to operate as intended after the test. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended. During the test, degradation of performance was however allowed. No change of actual operating state or stored data was allowed.

(3)Note: "C "means the EUT temporary loss of function was allowed, provided the function was self recoverable or could be restored by the operation of the controls.

(4)Additional Information :

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4.2.3.2 EFT/Burst Immunity Test Block Diagram

- 1. Power input.
- 6. Cable for Telecommunication Port or 9. Ground Reference Plane.
- 2. an insulating support ,10cm. Signal port. (between EUT and Peripheral .(Server or Host or .)
- 3. Coupling Clamp.
- 4. Coaxial Cable. 7. Signal Cable.
- 5. Power Cord.



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4.2.4 Surges, Common and Differential Mode Test: 4.2.4.1 Surges, Common and Differential Mode Test Data:

A.Operating Conditions of the EUT: Full Load

Test Date	Oct. 07 , 2015			
Test Specification	IEC 61000-4-5:2005			
Model Number	Series : N\A			
Power Supply Model Num.	PSA105R-050QL6	Manufacturer : N\A		
Climatic Condition	Ambient Temperature: 27°C Relative Humidity: 45 % RH			
	Atmospheric Pressure: <u>998</u> mbar			
Test Mode	Full Load			
Power Supply System	AC Power: <u>230</u> Vac <u>50</u> Hz			

Waveform: 1.2/50µs (8/20µs)		Repetition rate: 60 sec		Times: <u>5</u> times/each condition		
Applied Voltage(KV)	Mode	Test Line	Severity Level	Phase Angle	Test Result	Comments
±0.5	Differential Mode	L - N	1	0°/90°/180°/270°	А	
±1.0	Differential Mode	L - N	2	0°/90°/180°/270°	А	

Result:	■Complied	d			
Criterion Required:	0.5KV , 1KV	В	Criterion Met:	А	PASS

(1)Note: " A "means the EUT continued to operate as intended. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended.

(2)Note: "B "means the EUT continued to operate as intended after the test. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended. During the test, degradation of performance was however allowed. No change of actual operating state or stored data was allowed.

(3)Note: "C "means the EUT temporary loss of function was allowed, provided the function was self recoverable or could be restored by the operation of the controls.

(4)Additional Information :

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4.2.4.2 Surges, Common and Differential Mode Test Block Diagram

- 1. Ground Reference Plane.
- 6. Grounding Connection.
- 2. an insulating support ,10cm.
- 7. Cable for Telecommunication Port or Signal port.
- 3. Signal Cable.
- (between EUT and Peripheral .(Server or Host or.)



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4.2.5 RF Common Mode, 0.15~80MHz Test: 4.2.5.1 RF Common Mode, 0.15~80MHz Test Data: A.Operating Conditions of the EUT: <u>Full Load</u>

Test Date	Oct. 06 , 2015			
Test Specification	IEC 61000-4-6:2013			
Model Number		Series : N\A		
Power Supply Model Num.	PSAI05R-050QL6	Manufacturer : N\A		
Climatic Condition	Ambient Temperature: 21°C Relative Humidity: 45 % RH Atmospheric Pressure: 998 mbar			
Test Mode	Full Load			
Power Supply System	AC Power: <u>230</u> Vac <u>50</u> Hz			

Frequency Range : <u>0.15</u> MHz ~ <u>80</u> MHz		Test Voltage : <u>3</u> V	Modulation (AM 1kHz 80%)		
Sweep Rate $\therefore \le 1.5 \times 10^{-3}$ decades/s Step Size		$\therefore \le 1$ % of preceding frequency value		Dwell Time $\therefore 3.0$ s	
Frequency Range (MHz)		Tested Line		Test Result	
0.15~80	Power Line (M2)		А		

Result:	Complied	□ Does not comply			
Criterion Required:	А	Criterion Met:	А	PASS	

(1)Note: " A "means the EUT continued to operate as intended. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended.

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4.2.5.2 RF Common Mode Immunity Test Block Diagram


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4.2.6 Power Frequency Magnetic Field Immunity Test: 4.2.6.1 Power Frequency Magnetic Field Immunity Test Data: A.Operating Conditions of the EUT: Full Load

Test Date	Oct. 08 , 2015				
Test Specification	IEC 61000-4-8:2009				
Model Number		Series : N\A			
Power Supply Model Num.	PSA105R-050QL6	Manufacturer : N\A			
Climatic Condition Ambient Temperature: <u>27</u> °C Relative Hum Atmospheric Pressure: 996 mbar		elative Humidity: <u>45 %</u> RH			
Test Mode	Full Load				
Power Supply System	AC Power: <u>230</u> Vac <u>50</u> Hz				







Magnetic field frequency: 50 Hz	Continuous magnetic field strength: <u>1</u> A/m
Magnetic field direction	Testing result
X - Axis	А
Y – Axis	А
Z - Axis	А

Result:	Complied	\Box Does		
Criterion Required:	А	Criterion Met:	А	PASS

(1)Note: " A "means the EUT continued to operate as intended. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended.







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4.2.7 Voltage Dips and Interruptions Test:4.2.7.1 Voltage Dips and Interruptions Test Data:A.Operating Conditions of the EUT: Full Load

Test Date	Oct. 06 , 2015				
Test Specification	IEC 61000-4-11:2004	00-4-11:2004			
Model Number		Series : N\A			
Power Supply Model Num.	er Supply Model Num. PSAI05R-050QL6 Manufacturer				
Climatic Condition	Ambient Temperature: 27°C Relative Humidity: 45 % RH Atmospheric Pressure: 996 mbar				
Test Mode	Full Load				
Power Supply System	AC Power: <u>230</u> Vac <u>50</u> Hz				

Test mode	Voltage dips	Durations (ms)	Phase	Criterion Required	Result
Voltage interruptions	100%	5000	0°/180°	С	В
Valtage ding in 0/11	100%	10	0°~360°	В	А
Voltage dips in %U _T	30%	500	step 45	С	А

Result:	■ Complied	□ Does not comply
---------	------------	-------------------

(1)Note: " A "means the EUT continued to operate as intended. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended.

(2)Note: "B "means the EUT continued to operate as intended after the test. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended. During the test, degradation of performance was however allowed. No change of actual operating state or stored data was allowed.

(3)Note: "C "means the EUT temporary loss of function was allowed, provided the function was self recoverable or could be restored by the operation of the controls.

(4)Additional Information :



4.2.7.2 Voltage Interruptions and Voltage Dips Immunity Test Block Diagram



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5 EQUIPMENTS LIST FOR TESTING 5.1 Test Equipment for Conducted Emissions

Item	Name	Manufacturer	Model	ID(SN)	Calibration Date	Recommended Recal. Date
1	EMI Receiver	R&S	ESCI	13054418-001 (100941)	May. 04, 2015	May. 03, 2016
2	V-LISN	R&S	ENV216	13057719-001 (101029)	May. 13, 2015	May. 12, 2016
3	V-LISN	R&S	ENV216	13057719-002 (101030)	May. 13, 2015	May. 12, 2016

5.2 Test Equipment for Radiated Emissions Test

Item	Name	Manufacturer	Model	ID(SN)	Calibration Date	Recommended Recal. Date
1	EMI Receiver	R&S	ESIB7	13054417-001	Jul. 29, 2015	Jul. 28, 2016
2	EMI Receiver	R&S	ESU(20Hz~ 8GHz)	13054419-001(1 00234)	Apr. 26, 2015	Apr. 25, 2016
3	Bilog Antenna	SCHWARZBECK	VULB 9161	13057318-002	Jul. 02, 2015	Jul. 01, 2016
4	Bilog Antenna	SCHWARZBECK	VULB 9161	13057318-001	Jul. 27, 2015	Jul. 26, 2016
5	Amplifier	Agilent	8447D	13040715-001	Mar. 23, 2015	Mar. 22, 2016
6	Amplifier	Agilent	8447D	13040715-002	Mar. 31, 2015	Mar. 30, 2016

5.3 Test Equipment for Harmonics Current Emissions and Voltage Fluctuations, Flicker Test

Item	Name	Manufacturer	Model	ID(SN)	Calibration Date	Recommended Recal. Date	
1	Power Source	EMTEST	ACS 500N6	13046502-003	Mar. 05, 2015	Mar. 04, 2016	
2	Digital Power Analyzer	EMTEST	DPA 500N	13046502-003	Mar. 05, 2015	Mar. 04, 2016	

5.4 Test Equipment for ESD Test

Item	Name	Manufacturer	Model	ID(SN)	Calibration Date	Recommended Recal. Date	
1	ESD Simulator	Noiseken	ESS-2000	13033704-001	Jul. 04, 2015	Jul. 03, 2016	

5.5 Test Equipment for RS Test

Item	Name	Manufacturer	Model	ID(SN)	Calibration Date	Recommended Recal. Date
1	RF Power Amplifier	AR	120S1G4M1	333619	Jul. 07, 2015	Jul.06, 2016
2	RF Power Amplifier	AR	250W1000A	13052908-001	Jul. 07, 2015	Jul.06, 2016
3	RF Power Amplifier	AR	250A250A	13052907-001	Jul. 07, 2015	Jul.06, 2016
4	Signal Generator	R&S	IMS	13045401-001	Oct. 02, 2015	Oct.01, 2016
5	Bilog Antenna	AR	AT5080	326133	Jul. 07, 2015	Jul.06, 2016

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5.6 Test Equipment for EFT Test

Item	Name	Manufacturer	Model	ID(SN)	Calibration Date	Recommended Recal. Date		
1	EFT Generator / Clamp	Noiseken	FNS-AXII	13035301-001	Aug. 26, 2015	Aug. 27, 2016		
5.7 Test Equipment for SURGE Test								
Item	Name	Manufacturer	Model	ID(SN)	Calibration Date	Recommended Recal. Date		
1	LIGHTNING SURGE SIMULATOR	Noiseken	LSS-15AX	13033709-001	Jul. 15, 2015	Jul. 14, 2016		
5.8 Test Equipment for CS Test								
Item	Name	Manufacturer	Model	ID(SN)	Calibration Date	Recommended Recal. Date		
1	Signal Generator	IFR	2023	112282	Feb. 17, 2015	Feb. 16, 2016		
2	RF Power Amplifier	AR	25A250A	13052909-001	Aug. 22, 2015	Aug. 21, 2016		
3	Coupling Decoupling Network	Luethi	CDN L-801 M2/32	2785	Sep.24. 2015	Sep.25. 2016		
5.9 Test Equipment for MS Test								
Item	Name	Manufacturer	Model	ID(SN)	Calibration Date	Recommended Recal. Date		
	Oscillation a	nd EMC-PARTN	MIG0603O					

1	Surge and MS Test System	ER	MIG00030	13045801-001	Oct. 07, 2015	Oct. 06, 2016
2	Magnetic Field Antenna	EMC-PARTN ER	MF1000-1	13070701-001	N.C.R.	N.C.R.

5.10 Test Equipment for DIP Test

Item	Name	Manufacturer	Model	ID(SN)	Calibration Date	Recommended Recal. Date
1	EMS MULTIF UNCTION GENERATOR	TESEQ	NSG3040	13046509-001	Feb. 10, 2015	Feb. 09, 2016

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ANNEX A: PHOTOS

1. Conducted Emissions Test Setup Photos

Full Load





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2. Radiated Emissions Test Setup Photos (30MHz~1GHz)

Full Load



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3. Harmonics Current Emissions Test Setup Photo



4. Voltage Fluctuations and Flicker Test Setup Photo



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5. Electrostatic Discharge Immunity Test Setup Photo



6. RF Radiated Fields Immunity Test Setup Photo



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7. EFT/Burst Immunity Test Setup Photo



8. Surge Immunity Test Setup Photo



ETC TAIWAN TESTING AND CERTIFICATION CENTER Report No.: 22-03-MAT-104 EMC TESTING DEPARTMENT Photos Page: A6/A9

9. RF Common Mode Immunity Test Setup Photo



ETC TAIWAN TESTING AND CERTIFICATION CENTER Report No.: 22-03-MAT-104 EMC TESTING DEPARTMENT Photos Page: A7/A9

10. Power Frequency Magnetic Field Immunity Test Setup Photo



11. Voltage Interruptions and Voltage Dips Immunity Test Setup Photo



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12. Outside view 1 of EUT



13. Outside view 2 of EUT









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APPENDIX I

The test data is recorded from Feb. 15 to Feb. 17, 2017 for evaluation purposes only. The test data may be duplicated completely for legal use with the approval of the applicant. It should not be reproduced except in full, without the written approval of our laboratory.

*Adds EN 55032 to re-test.

1. GENERAL SPECIFICATION

1.1 Tested Peripheral:

The EUT was pre-tested and final tested under the following mode:

Product	Manufacturer	Model No.	I/O Cable

2The Worst Mode for test:

2.1 Testing Setup Block Diagram



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3SUMMARY OF TEST RESULTS

3.1 Emissions: 3.1.1 Conducted Emissions PASS QP EMI value to the limit: -14.04 dB at 0.1940 MHz 3.1.2 Radiated Emissions PASS QP EMI value to the limit: -3.69 dB at 99.1584 MHz 3.1.3 Harmonics Current Emissions □-N/A Adds EN 55032 standard, after estimating, it didn't need to re-test. 3.1.4 Voltage Fluctuations and Flicker □-N/A Adds EN 55032 standard, after estimating, it didn't need to re-test.

3.2Summary of test Results and Applied Level:

Manufacturer level requirements:

Summary of test Results and Applied Level							
	Emission						
Test Standard	Test Item	Test Result	Applied Level and M.U.				
EN 55032:2015,Class B	Radiated Emission	PASS	Class B @30MHz~1GHz, U=±4.98dB @1GHz~6GHz, U=±5.18dB				
EN 55032:2015,Class B	Conducted Emission	PASS	Class B @AC Port: 0.15MHz~30MHz, U=±2.92dB @ISN: 0.15MHz~30MHz, U=±3.00dB				
EN 61000-3-2:2006 +A1:2009 +A2:2009 / IEC 61000-3-2:2005 +A1:2008 +A2:2009, Class A	Harmonic Current Emission	N/A	Adds EN 55032 standard, after estimating, it didn't need to re-test.				
EN 61000-3-3:2013 / IEC 61000-3-3:2013	Voltage Fluctuation and Flicker Test	N/A	Adds EN 55032 standard, after estimating, it didn't need to re-test.				

Note : Measurement uncertainty $U=\pm X$. Means the expanded measure uncertainty $U=\pm X$, the coverage factor k=2, approximately a 95% level of confidence.



No.	Frequency	Reading	Detector	Corrected	Result	Limit	Margin	Comment
	(MHz)	(dBuV)		dB	(dBuV)	(dBuV)	(dB)	
1	0.1940	40.17	QP	9.65	49.82	63.86	-14.04	
2	0.2540	35.70	QP	9.65	45.35	61.63	-16.28	
3	0.7620	30.56	QP	9.66	40.22	56.00	-15.78	
4	1.2700	31.79	QP	9.66	41.45	56.00	-14.55	
5	2.2180	31.10	QP	9.69	40.79	56.00	-15.21	
6	10.8380	21.63	QP	9.88	31.51	60.00	-28.49	

Notes: 1) Place of measurement: EMC LAB. of the ETC (CE-04)

2) The EUT was placed 0.8m above reference ground plane.

3) The expanded measure uncertainty, mean the coverage factor k=2, approximately a 95% level of confidence.

±2.92dB(0.15MHz~30MHz)

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(Phase:N) AC Power: 230 Vac 50 Hz



No.	Frequency	Reading	Detector	Corrected	Result	Limit	Margin	Comment
	(MHz)	(dBuV)		dB	(dBuV)	(dBuV)	(dB)	
1	0.1900	38.72	QP	9.63	48.35	64.04	-15.69	
2	0.2460	34.13	QP	9.63	43.76	61.89	-18.13	
3	0.3820	25.20	QP	9.63	34.83	58.24	-23.41	
4	0.9540	25.43	QP	9.65	35.08	56.00	-20.92	
5	2.0300	23.90	QP	9.67	33.57	56.00	-22.43	
6	6.9660	20.73	QP	9.81	30.54	60.00	-29.46	

Notes: 1) Place of measurement: EMC LAB. of the ETC (CE-04)

2) The EUT was placed 0.8m above reference ground plane.

3) The expanded measure uncertainty, mean the coverage factor k=2, approximately a 95% level of confidence.

 ± 2.92 dB(0.15MHz~30MHz)

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4.1.2 Radiated Emissions Test:

4.1.2.1 Radiated Emissions Test Data:

A. Operating Conditions of the EUT: Full Load

Test Date: $\underline{2017/02/15}$ Temperature: $\underline{26 \ ^{\circ}C}$ Humidity: $\underline{60 \ \%}$ Measurement Distance: $\underline{10m}$ (30MHz~1GHz), AC Power:230Vac50HzHorizontal



No.	Frequency	Reading	Detector	Corrected	Result	Limit	Margin	Height	Degree	Comment
	(MHz)	(dBuV/m)		dB/m	(dBuV/m)	(dBuV/m)	(dB)	(cm)	(°)	
1	33.1090	41.55	QP	-17.00	24.55	30.00	-5.45	300	262	
2	54.8718	35.57	QP	-20.25	15.32	30.00	-14.68	300	79	
3	98.3974	39.82	QP	-18.95	20.87	30.00	-9.13	398	235	
4	120.1603	34.14	QP	-15.66	18.48	30.00	-11.52	300	23	
5	149.6954	39.98	QP	-16.92	23.06	30.00	-6.94	398	360	
6	185.4487	38.65	QP	-19.67	18.98	30.00	-11.02	398	360	

- Notes: 1) Place of Measurement: <u>Measuring site of the ETC (1F)</u>
 - 2) Measurement Distance: 10 m
 - 3) Height of table on which the EUT was placed: 0.8 m
 - 4) Height of Receiving Antenna: <u>1 4 m</u>
 - 5) The expanded measure uncertainty, mean the coverage factor k=2, approximately a 95% level of confidence.

+ 4.94dB / - 4.94dB (30MHz $\leq f \leq$ 300MHz)

- + 4.94dB / 4.94dB (300MHz $\leq f \leq 1$ GHz)
- + 5.1dB / 5.1dB (1GHz $\leq f \leq$ 6GHz)
- + 4.58dB / 4.58dB (6GHz $\leq f \leq$ 18GHz)

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Vertical ,AC Power: 230 Vac 50 Hz



No.	Frequency	Reading	Detector	Corrected	Result	Limit	Margin	Height	Degree	Comment
	(MHz)	(dBuV/m)		dB/m	(dBuV/m)	(dBuV/m)	(dB)	(cm)	(°)	
1	34.0080	38.63	QP	-17.46	21.17	30.00	-8.83	199	359	
2	55.2705	42.85	QP	-20.48	22.37	30.00	-7.63	100	309	
3	99.1584	45.03	QP	-18.72	26.31	30.00	-3.69	199	36	
4	133.0261	35.79	QP	-15.87	19.92	30.00	-10.08	199	79	
5	183.5671	42.81	QP	-19.38	23.43	30.00	-6.57	100	360	
6	197.1743	37.05	QP	-19.13	17.92	30.00	-12.08	100	360	

Notes: 1) Place of Measurement: Measuring site of the ETC (1F)

2) Measurement Distance: <u>10 m</u>

3) Height of table on which the EUT was placed: 0.8 m

4) Height of Receiving Antenna: <u>1 - 4 m</u>

5) The expanded measure uncertainty, mean the coverage factor k=2, approximately a 95% level of confidence.

 $+ 4.98 dB / - 4.98 dB (30 MHz) \leq f \leq 300 MHz$

+ 4.98dB / - 4.98dB (300MHz $\leq f \leq 1$ GHz)

+ 5.18dB / - 5.18dB (1GHz $\leq f \leq 6$ GHz)

+ 4.9dB / - 4.9dB (6GHz $\leq f \leq$ 18GHz)

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5EQUIPMENTS LIST FOR TESTING

5.1 Test Equipment for Conducted Emissions

Item	Name	Manufacturer	Model	ID(SN)	Calibration Date	Recommended Recal. Date
1	EMI Receiver	R&S	ESCI	13054418-001 (100941)	Jan.16,2017	Jan.15,2018
2	V-LISN	R&S	ENV216	13057719-002 (101030)	Aug.11,2016	Aug.10,2017
3	Control Computer	Lemel	WLIEG31G8CP	13080462-004	N/A	N/A
4	Software	FARAD	EZ-EMC	EZEMCCE04	N/A	N/A

5.2 Test Equipment for Radiated Emissions Test

Item	Name	Manufacturer	Model	ID(SN)	Calibration Date	Recommended Recal. Date
1	EMI Receiver	R&S	ESIB7	13054417-001	Aug. 30, 2016	Aug. 29, 2017
2	EMI Receiver	R&S	ESU(20Hz~8GH z)	13054419-001(1 00234)	Apr. 23, 2016	Apr. 22, 2017
3	Bilog Hybrid Antenna With 5dB Attenuator	ETC&JYEB AO	MCTD 2786B&FAT-NM 5NF5T3G2WXX	BLB16M04003 &JB-5-002	Mar. 04, 2016	Mar. 03, 2017
4	Bilog Hybrid Antenna With 5dB Attenuator	ETC&JYEB AO	MCTD 2786B&FAT-NM 5NF5T3G2WXX	BLB16M04003 &JB-5-003	Mar. 04, 2016	Mar. 03, 2017
5	Amplifier	EMCI	EMC9135	980345	Oct. 11, 2016	Oct. 10, 2017
6	Amplifier	EMCI	EMC9135	980346	Oct. 11, 2016	Oct. 10, 2017
7	Control Computer	DELL	INSPIRON 660	13080491-001	N/A	N/A
8	Software	FARAD	EZ-EMC	EZEMCN5	N/A	N/A

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ANNEX B: PHOTOS

1. Conducted Emissions Test Setup Photos

Full Load





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2. Radiated Emissions Test Setup Photos (30MHz~1GHz)

Full Load





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APPENDIX II

The test data is recorded from Mar. 25 to Apr. 11, 2022 for evaluation purposes only. The test data may be duplicated completely for legal use with the approval of the applicant. It should not be reproduced except in full, without the written approval of our laboratory.

*Adds EN 55035 standard and deletes EN 55022, EN 55024 standard.

*As above differences, it re-tests RS, Surge and CS test items for this report.

*Updates standard for detailed see as P.4.

1GENERAL SPECIFICATION

1.1 Tested Peripheral:

The EUT was pre-tested and final tested under the following mode:

Product	Manufacturer	Model No.	I/O Cable
Dummy Load			1.8m, Unshielded
Multimeter	KILTER	KILTER 370A	1.6m, Undetachable

2The Worst Mode for test:

2.1 Testing Setup Block Diagram



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3SUMMARY OF TEST RESULTS

3.1 Emissions:

3.1.1 Conducted Emissions □-N/A Adds EN 55035 standard, after estimating, it didn't need to re-test.

3.1.2 Radiated Emissions □-N/A Adds EN 55035 standard, after estimating, it didn't need to re-test.

3.1.3 Harmonics Current Emissions □-N/A Adds EN 55035 standard, after estimating, it didn't need to re-test.

3.1.4 Voltage Fluctuations and Flicker □-N/A Adds EN 55035 standard, after estimating, it didn't need to re-test.

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3.2 Immunity:

3.2.1 Immunity Criteria:

The results of all of the immunity tests performed on the EUT were evaluated according to the following criteria, and according to the manufacturer's specifications for the EUT:

- **Performance criterion A:** The EUT continued to operate as intended. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended.
- **Performance criterion B:** The EUT continued to operate as intended after the test. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended. During the test, degradation of performance was however allowed. No change of actual operating state or stored data was allowed.
- **Performance criterion C:** Temporary loss of function was allowed, provided the function was self recoverable or could be restored by the operation of the controls.

3.2.2 Electrostatic Discharge Immunity: N/A Adds EN 55035 standard, after estimating, it didn't need to re-test.

□ - No Degradation of Function

\square - Distortion of Function

 \square - Error of Function

3.2.3 RF Radiated Fields Immunity:

- - No Degradation of Function
- □ Distortion of Function
- \Box Error of Function

Requirement: Criterion B (or better)

- Satisfies Criterion A
- Satisfies Criterion B
- Satisfies Criterion C

Requirement: Criterion A

- Satisfies Criterion A
- Satisfies Criterion B
- Satisfies Criterion C

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3.2.4 EFT/Burst Immunity: N/A Adds EN 55035 standard, after estimating, it didn't need to re-test.

- □ No Degradation of Function
- □ Distortion of Function
- □ Error of Function

3.2.5 Surge Immunity:

- - No Degradation of Function
- \square Distortion of Function
- \square Error of Function

3.2.6 RF Common Mode Immunity:

- No Degradation of Function
- \square Distortion of Function
- \Box Error of Function

Requirement: Criterion B (or better)

- Satisfies Criterion A
- Satisfies Criterion B
- Satisfies Criterion C

Requirement: Criterion B (or better)

- Satisfies Criterion A
- Satisfies Criterion B
- Satisfies Criterion C

Requirement: Criterion A

- Satisfies Criterion A
- Satisfies Criterion B
- Satisfies Criterion C

3.2.7 Power Frequency Magnetic Field Immunity: N/A Adds EN 55035 standard, after estimating, it didn't need to re-test.

- □ No Degradation of Function
- \Box Distortion of Function
- □ Error of Function

- Satisfies Criterion A

Requirement: Criterion A

- Satisfies Criterion B
- Satisfies Criterion C

3.2.8 Voltage Interruptions and Voltage Dips Immunity: N/A Adds EN 55035 standard, after estimating, it didn't need to re-test.

- □ No Degradation of Function
- □ Distortion of Function
- \square Error of Function

- **Requirement: Criterion C (or better)**
- Satisfies Criterion A
- Satisfies Criterion B
- Satisfies Criterion C

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3.3Summary of test Results and Applied Level:

Manufacturer level requirements:

Summary of test Results and Applied Level								
	Emission							
Test Standard	Test Item	Test Result	Applied Level and M.U.					
EN 55032:2015 EN 55032:2015+A11:2020 CISPR32:2015 CISPR32:2015+A1:2019 AS/NZS CISPR 32:2015, Class B	Radiated Emission	N/A	Adds EN 55035 standard, after estimating, it didn't need to re-test.					
EN 55032:2015 EN 55032:2015+A11:2020 CISPR32:2015 CISPR32:2015+A1:2019 AS/NZS CISPR 32:2015, Class B	Conducted Emission	N/A	Adds EN 55035 standard, after estimating, it didn't need to re-test.					
EN 61000-3-2:2006 +A1:2009 +A2:2009 / IEC 61000-3-2:2005 +A1:2008 +A2:2009, Class A	Harmonic Current Emission	N/A	Adds EN 55035 standard, after estimating, it didn't need to re-test.					
EN 61000-3-3:2013 / IEC 61000-3-3:2013	Voltage Fluctuation and Flicker Test	N/A	Adds EN 55035 standard, after estimating, it didn't need to re-test.					
	Immunity [EN 55035:2017+4	A11:2020]						
EN 61000-4-2:2009 / IEC 61000-4-2:2008	Electrostatic Discharge Test (ESD)	N/A	Adds EN 55035 standard, after estimating, it didn't need to re-test.					
EN IEC 61000-4-3:2020 / IEC 61000-4-3:2020	Radiated , RF Immunity (RS) (RS03-10M 1F-N6)	PASS	 @Frequency: <u>80MHz-5000MHz</u> @3V/m (Unmodulated), 1KHz Amplitude Modulated with modulation depth 80% Field strength: 80M-6GHz: 1.80 dB Acoustic measurement:80M-6GHz: 1.98dB (SPL) 					
EN 61000-4-4:2012 / IEC 61000-4-4:2012	Electrical Fast Transient/burst Test (EFT)	N/A	Adds EN 55035 standard, after estimating, it didn't need to re-test.					
EN 61000-4-5:2014+A1:2017 / IEC 61000-4-5:2014/AMD1:2017	Surge Immunity IMU3000+CDN3000A-08-32 (SURGE02-10M B1)	PASS	 @Power port : <u>±0.5KV</u> / <u>±1KV</u> @I/O Port :<u>N/A</u> Open circuit voltage front time: 0.19 us Open circuit peak voltage: 7.56 % Open circuit voltage duration: 0.49 us 					
EN 61000-4-6:2014 / IEC 61000-4-6:2013/AC: 2015	Conducted , RF Immunity (CS) (CS01-10M B1)	PASS	 @Frequency: <u>0.15MHz-80MHz</u> @3~1V/m (Unmodulated), 1KHz Amplitude Modulated with modulation depth 80% 150K-230MHz, M2(TESEQ): 1.65 dB 					
EN 61000-4-8:2010 / IEC 61000-4-8:2009	Power Frequency Magnetic Field (MS)	N/A	Adds EN 55035 standard, after estimating, it didn't need to re-test.					
EN IEC 61000-4-11:2020 / IEC 61000-4-11:2020	Voltage dips,short interruptions and voltage variations on power supply input lines	N/A	Adds EN 55035 standard, after estimating, it didn't need to re-test.					

Note : Measurement uncertainty $U=\pm X$. Means the expanded measure uncertainty $U=\pm X$, the coverage factor k=2, approximately a 95% level of confidence.

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4TEST DATA & RELATED INFORMATIONS

4.1 Immunity:

4.1.1 RF Radiated Fields Immunity Test:

4.1.1.1RF Radiated Fields Immunity Test Data:

A. Operating Conditions of the EUT

Project number	22-03-MAT-104	Test Dated	Apr. 09, 2022				
Test Specification	IEC 61000-4-3 / EN 61000-4-3	IEC 61000-4-3 / EN 61000-4-3					
Test Site	RS03-10M 1F-N6						
Climatic Condition	Ambient Temperature: 23 °C Relative Humidity: 52 %RH						
	Atmospheric Pressure: <u>990</u> mbar						
Power Supply System	■ AC Power: <u>230</u> Vac <u>50</u> Hz □ I	DC Power:	√dc				
Test Mode	Full Load						
Test Set-up	■ Table-top Equipment □ Floor-standing Equipment						
Test Engineer	Vincent Chang						

Frequency Range : <u>80</u> MHz ~ <u>10</u>	00 MHz Field St	Field Strength : <u>3</u> V/m		Modulation (AM 1kHz 80%)	
Sweep Rate $\therefore \le 1.5 \times 10^{-3}$ decades/s	Step Size $\therefore \le 1 \%$	of preceding frequen	ncy value	Dwell Time $: 5 \text{ s}$	
Frequency Range (MHz)	Polarization of Antenna	EUT Position (Angle)	Test Result	Comments	
<u>80</u> MHz ~ <u>1000</u> MHz	Vertical	0	А		
<u>80</u> MHz ~ <u>1000</u> MHz	Vertical	90	А		
<u>80</u> MHz ~ <u>1000</u> MHz	Vertical	180	А		
<u>80</u> MHz ~ <u>1000</u> MHz	Vertical	270	А		
<u>80</u> MHz ~ <u>1000</u> MHz	Horizontal	0	А		
<u>80</u> MHz ~ <u>1000</u> MHz	Horizontal	90	А		
<u>80</u> MHz ~ <u>1000</u> MHz	Horizontal	180	А		
<u>80</u> MHz ~ <u>1000</u> MHz	Horizontal	270	А		

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Frequency Range : <u>1800/2600/3500/</u>	5000 MHz Field St	rength $: 3 \text{V/m}$	Modulation	a (AM 1kHz 80%)
Sweep Rate $\therefore \le 1.5 \times 10^{-3}$ decades/s	Step Size $\therefore \le 1 \%$	of preceding frequen	icy value	Dwell Time $\div 5$ s
Frequency Range (MHz)	Polarization of Antenna	EUT Position (Angle)	Test Result	Comments
	Vertical	0	А	
	Vertical	90	А	
	Vertical	180	А	
<u>1800</u> MHz ±1% 2600 MHz ±1%	Vertical	270	А	
3500 MHz ±1% 5000 MHz ±1%	Horizontal	0	А	
	Horizontal	90	А	
	Horizontal	180	А	
	Horizontal	270	А	

Result:	■ Complied	\Box Does not comply		
Criterion Required:	A	Criterion Met:	A	
(1) Note: "A "means the FUT continued to ensure as intended. No description of nonfermance on loss of function mas				

(1)Note: " A "means the EUT continued to operate as intended. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended.

(2)Note: "B "means the EUT continued to operate as intended after the test. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended. During the test, degradation of performance was however allowed. No change of actual operating state or stored data was allowed.

(3)Note: "C "means the EUT temporary loss of function was allowed, provided the function was self recoverable or could be restored by the operation of the controls.

(4)Additional Information :

The frequency range is scaned as specified. However, when specified in Annex A, an additional comprehensive functional test shall carried out at a limited number of frequencies. And additional frequencies tested for Korean KN24. The selected frequencies are : 80, 120, 145, 160, 230, 375, 434, 435, 460, 600, 814, 835, 863, and $900MHz(\pm1\%)$).

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4.1.2 Surge Immunity Test:

4.1.2.1Surge Immunity Test Data:

A. Operating Conditions of the EUT

Project number	22-03-MAT-104	Test Dated	Apr. 11, 2022		
Test Specification	IEC 61000-4-5 / EN 61000-4-5				
Test Site	SURGE02 – 10M B1				
Climatic Condition	Ambient Temperature: 23 °C Relative Humidity: 52 % RH				
Climatic Condition	Atmospheric Pressure: <u>984</u> mbar				
Power Supply System	AC Power: <u>230</u> Vac <u>50</u> Hz				
Test Mode	Full Load				
Test Set-up	■ Table-top Equipment□ Floor-standing Equipment				
Test Engineer	Vincent Chang				

Waveform: 1.2/50µs (8/20µs)

Repetition rate: 60 sec

Times: 5 times/each condition

Applied Voltage(KV)	Mode	Test Line	Severity Level	Phase Angle	Test Result	Comments
±0.5	Differential Mode	L - N	1	0°/90°/180°/270°	А	
±1.0	Differential Mode	L - N	2	0°/90°/180°/270°	А	

Result:	■Complied			
Criterion Required:	0.5KV , 1KV	В	Criterion Met:	А

(1)Note: " A "means the EUT continued to operate as intended. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended.

(2)Note: "B "means the EUT continued to operate as intended after the test. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended. During the test, degradation of performance was however allowed. No change of actual operating state or stored data was allowed.

(3)Note: "C "means the EUT temporary loss of function was allowed, provided the function was self recoverable or could be restored by the operation of the controls.

(4)Additional Information :

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4.1.3 RF Common Mode, 0.15~80MHz Test:

4.1.3.1RF Common Mode, 0.15~80MHz Test Data:

A. Operating Conditions of the EUT:

Project number	22-03-MAT-104	Test Dated	Apr. 01, 2022				
Test Specification	IEC 61000-4-6 / EN 61000-4-6	EC 61000-4-6 / EN 61000-4-6					
Test Site	CS01 – 10M B1	CS01 – 10M B1					
Climatic Condition	Ambient Temperature: 22 °C Relative Humidity: 54 % RH						
	Atmospheric Pressure: <u>989</u> mbar						
Power Supply System	■ AC Power: <u>230</u> Vac <u>50</u> Hz □ I	OC Power: V	√dc				
Test Mode	Full Load						
Test Set-up	□ Table-top Equipment Floor-standing Equipment						
Test Engineer	Vincent Chang						

	: <u>0.15</u> MHz ~ <u>10</u> MHz		Test Voltage	: <u>3</u> V			
Frequency Range	: <u>10</u> MHz ~ <u>30</u> MHz		Test Voltage	$: \underline{3} V$ to $\underline{1} V$	Modulation (AM 1kHz 80%)		
	: <u>30</u> MHz ~ <u>80</u> MH	Z	Test Voltage	: <u>1</u> V			
Sweep Rate $\therefore \leq$	Step Size	Step Size $\therefore \le 1$ % of preceding frequency val			Dwell Time $: 3.0$ s		
Frequency Range (MHz)			Tested Line			Test Result	
0.15~80			Power Line (M2)		А		

Result:	Complied	\Box Does not comply		
Criterion Required:	А	Criterion Met:	А	PASS

(1)Note: " A "means the EUT continued to operate as intended. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended.

(2)Note: "B "means the EUT continued to operate as intended after the test. No degradation of performance or loss of function was allowed below a performance level specified by the manufacturer, when the EUT was used as intended. During the test, degradation of performance was however allowed. No change of actual operating state or stored data was allowed.

(3)Note: "C "means the EUT temporary loss of function was allowed, provided the function was self recoverable or could be restored by the operation of the controls.

(4)Additional Information :

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5EQUIPMENTS LIST FOR TESTING

5.1 Test Equipment for RS Test

Item	Name	Manufacturer	Model	ID(SN)	Calibration Date	Recommended Recal. Date
1	ANTENNA	SCHWARZB ECK	VULP 9118E	13057619-001	Mar.02,2022	Mar.01,2023
2	Horn Antenna	SCHWARZB ECK	VULB9120D	13057318-003	Mar.15,2022	Mar.14,2023
3	Power Meter	BOONTON	4532	13050615-001	Nov.14,2021	Nov.13,2022
4	Signal Generator	R&S	SMR20	13051711-001	May.16,2021	May.15,2022
5	Power Amplifier	AMETEK	80RF 1000-300	13052925-001	Jan.06,2022	Jan.05,2023
6	Power Amplifier	AR	50S1G4AM1	13052903-001	Apr.28,2021	Apr.27,2022
7	Power Sensor	BOONTON	51011	13053510-003	Nov.14,2021	Nov.13,2022
8	Power Sensor	BOONTON	51011	13053510-001	Nov.14,2021	Nov.13,2022
9	Traveling Wave Tube Amplifier	AR	20T4G18A	13052912-001	Apr.28,2021	Apr.27,2022
10	Signal Generator	KEYSIGHT	N5171B	13051724-001	Nov.29,2021	Nov.28,2022
11	Control Computer	DELL	OPTIPLEX 3050	13084016-002	N/A	N/A
12	Software	AUDIX	i2	20160217b	N/A	N/A

5.2 Test Equipment for SURGE Test

Item	Name	Manufacturer	Model	ID(SN)	Calibration Date	Recommended Recal. Date
1	Surge Simulator	EMC Partner	IMU3000	13046511-001	Jul.28,2021	Jul.27,2022
2	Surge CDN	EMC Partner	CDN3000A- 08-32	13057747-001	Jul.28,2021	Jul.27,2022

5.3 Test Equipment for CS Test

Item	Name	Manufacturer	Model	ID(SN)	Calibration Date	Recommended Recal. Date
1	Coupling And Decoupling Network	TESEQ	CDN M016	13057749-001	Jan.11,2022	Jan.10,2023
2	Compact Immunity Test System	TESEQ	NSG 4070B-80	46509	Apr.05,2021	Apr.04,2022
3	6dB 12W Attenuator	RADIALL	R415706	743RS-01	Oct.26,2021	Oct.25,2022



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ANNEX C: PHOTOS

1. RF Radiated Fields Immunity Test Setup Photo

(Front)



(Back)



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2. Surge Immunity Test Setup Photo



3. RF Common Mode Immunity Test Setup Photo

(Power)

